TOSHIBA

TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π-MOSVI)

2SK4111

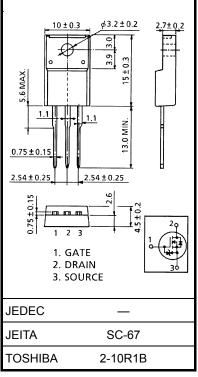
Switching Regulator Applications

• Low drain-source ON resistance: $RDS(ON) = 0.54 \Omega$ (typ.)

- High forward transfer admittance: $|Y_{fs}| = 8.5S$ (typ.)
- Low leakage current: $I_{DSS} = 100 \ \mu A \ (max) \ (V_{DS} = 600 \ V)$
- Enhancement mode: $V_{th} = 2.0$ to 4.0 V ($V_{DS} = 10 \text{ V}$, $I_D = 1 \text{ mA}$)

Chara	cteristics	Symbol	Rating	Unit
Drain-source volta	ge	V _{DSS}	600	V
Drain-gate voltage	$(R_{GS} = 20 \text{ k}\Omega)$	V _{DGR}	600	V
Gate-source voltage	je	V _{GSS}	±30	V
	DC (Note 1)	۱ _D	10	
Drain current	Pulse (t = 1 ms) (Note 1)	I _{DP}	40	A
Drain power dissip	Drain power dissipation (Tc = 25°C) Single pulse avalanche energy (Note 2) Avalanche current		45	W
Single pulse avala			363	mJ
Avalanche current			10	А
Repetitive avalance	he energy (Note 3)	E _{AR}	4.5	mJ
Channel temperat	Channel temperature		150	°C
tas Storage temperatu	re range	T _{stg}	-55 to 150	°C

Absolute Maximum Ratings (Ta = 25°C)



Weight: 1.9 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	2.78	°C/W
Thermal resistance, channel to ambient	R _{th (ch-a)}	62.5	°C/W

Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2: $V_{DD} = 90 \text{ V}, \text{ T}_{ch} = 25^{\circ}\text{C}(\text{initial}), \text{ L} = 6.36 \text{ mH}, \text{ I}_{AR} = 10 \text{ A}, \text{ R}_{G} = 25 \Omega$

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Please handle with caution.

Unit: mm

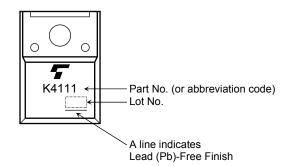
Electrical Characteristics (Ta = 25°C)

Char	acteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cur	rrent	I _{GSS}	$V_{GS}=\pm 25~V,~V_{DS}=0~V$	— — ±10		μA	
Gate-source brea	akdown voltage	V (BR) GSS	$I_G=\pm 10~\mu A,~V_{DS}=0~V$	±30 — —		V	
Drain cut-off curr	ent	I _{DSS}	$V_{DS} = 600 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$	_		100	μA
Drain-source bre	akdown voltage	V (BR) DSS	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	600		_	V
Gate threshold ve	oltage	V _{th}	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 1 \text{ mA}$	2.0		4.0	V
Drain-source ON	resistance	R _{DS (ON)}	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 5 \text{ A}$	10 V, I _D = 5 A 0.54		0.75	Ω
Forward transfer	admittance	Y _{fs}	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 5 \text{ A}$	2.4	8.5	_	S
Input capacitance	e	C _{iss}		_	1500	_	
Reverse transfer capacitance		C _{rss}	$V_{DS} = 25 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ f} = 1 \text{ MHz}$	_	15	_	pF
Output capacitan	Dutput capacitance				180	_	
Switching time	Rise time	tr	$\begin{array}{c} 10 \text{ V} \\ \text{V}_{GS} \\ 0 \text{ V} \\ 50 \Omega \\ \Psi \\$	_	22		• ns
	Turn-on time	t _{on}		_	50	_	
	Fall time	t _f			36		
	Turn-off time	t _{off}		_	180		
Total gate charge Qg		Qg			42		
Gate-source charge		Q _{gs}	$V_{DD} \approx 400 \text{ V}, \text{ V}_{GS} = 10 \text{ V}, \text{ I}_{D} = 10 \text{ A}$		23		nC
Gate-drain charge		Q _{gd}			19		

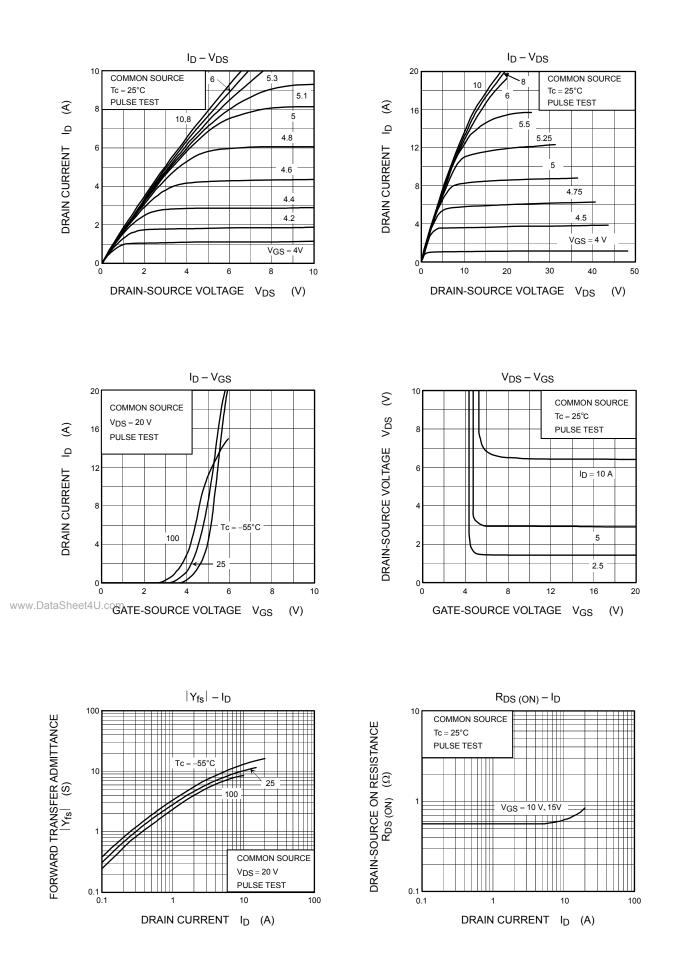
Source-Drain Ratings and Characteristics (Ta = 25°C)

	Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
	Continuous drain reverse current (Note 1)	I _{DR}	_		_	10	А
www.Datas	Pulse drain reverse current (Note 1)	I _{DRP}	—			40	А
	Forward voltage (diode)	V _{DSF}	$I_{DR} = 10 \text{ A}, V_{GS} = 0 \text{ V}$		—	-1.7	V
	Reverse recovery time	t _{rr}	$I_{DR} = 10 \text{ A}, V_{GS} = 0 \text{ V},$		1300	_	ns
	Reverse recovery charge	Q _{rr}	dI _{DR} /dt = 100 A/μs	_	16		μC

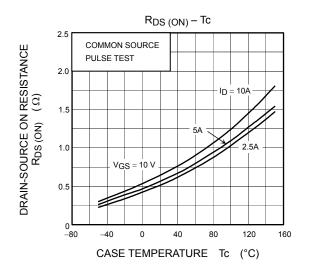
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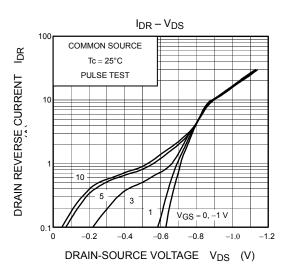


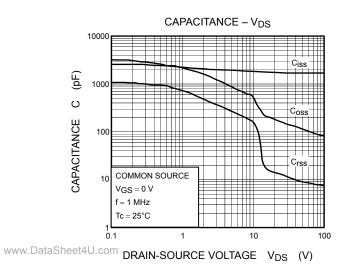
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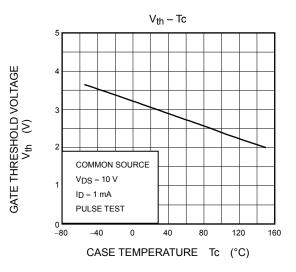


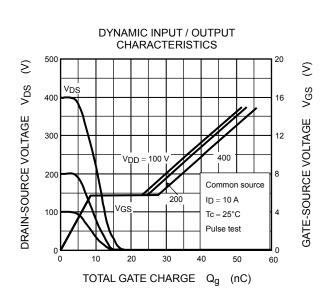
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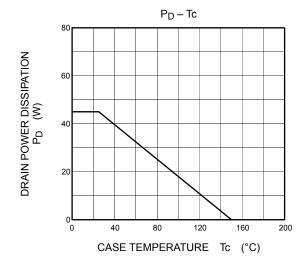


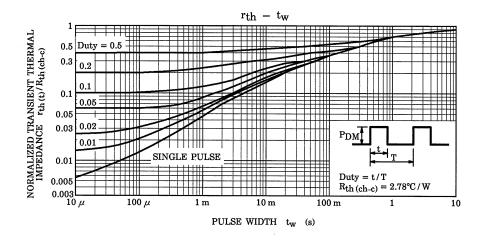


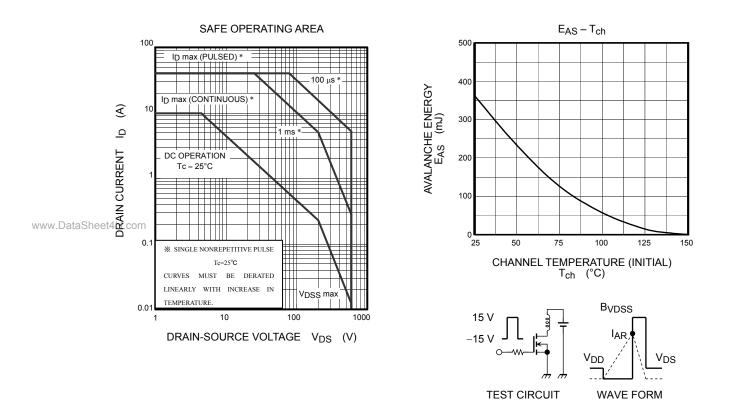












 $\begin{array}{l} \mathsf{R}_{G} = 25 \ \Omega \\ \mathsf{V}_{DD} = 90 \ \mathsf{V}, \ \mathsf{L} = 6.36 \mathsf{mH} \end{array} \qquad \mathsf{E}_{AS} = \frac{1}{2} \cdot \mathsf{L} \cdot \mathsf{I}^{2} \cdot \left(\frac{\mathsf{B}_{VDSS}}{\mathsf{B}_{VDSS} - \mathsf{V}_{DD}} \right) \end{array}$

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20070701-EN GENERAL

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